PCN Number:			20131203000						PCN Date:		12/09/2013		
Title: Conversion t			o Cu bond wire										
Customer Contact:			PCN Manager		Phone: +1(214)48		80-6	037	Dept:	Quality Services			
Proposed 1 st Ship Da			ite:	03/09/2014	Estim	nated Sample Avai			bility:	12/05/2013			
Cha	Change Type:												
	Asse	mbly Site						Assembly Materials					
Design				Electrical	Specificat				chanical Specification				
Test Site				Packing/S				Test Process					
Щ	Wafer Bump Site			Wafer Bur	<u> </u>		Vafer Bump Process						
Wafer Fab Site				Wafer Fab Materials					Wafer Fab Process				
				Part number change									
_					PCN De	etaiis							
Des	script	ion of Chang	je:										
Texas Instruments is pleased to announce the qualification of Cu as a bond wire option for the selected devices shown below. All listed devices will remain in current assembly facility and there will be no other BOM changes.													
Reason for Change:													
Continuity of supply. 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties 2) Maximize flexibility within our Assembly/Test production sites. 3) Cu is easier to obtain and stock													
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):													
None													
Changes to product identification resulting from this PCN:													
None													
Product Affected													
TR	F3705	IRGER	TRF3705IRGET TRF37T05IRGER						TRF37T05IRGET				
Qualification Data													
This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.													
Qual Vehicle: TRF37T05IRGE (MSL 2-260C)													

Package Construction Details

Mold Compound:

Bond Wire:

Mount Compound:

Clark-AT

NiPdAuAg

24-RGE, QFN

Assembly Site:

Lead Finish

Pins-Designator, Family:

4208625

4207768

0.80Mil Cu

Qualification: Plan Test Results				
Reliability Test	Conditions	Sample Size / Fail		
Electrical Characterization	Side by Side (Au vs. Cu)	Pass		
ESD CDM	+/- 250V, 500V	3/0		
ESD HBM	+/- 500V, 1000V, 1500V	3/0		
Latch-up	(per JESD78)	6/0		

Reference Qualification Data									
This qualification has been developed for the validation of this change. The qualification data									
validates that the proposed change meets the applicable released technical specifications.						ions.			
Qual Vehicle: CDC750RGC (MSL 3-260C)									
Package Construction Details									
Assembly Site:	Cla	Clark AT Mold Compound:			4208625				
# Pins-Designator, Family:	64-	-RGC, QFN	Mount Compound:		4207768				
Lead Finish	NiP	iPdAu Bond Wire:			0.8mil Cu/0.8mil Au				
Qualification: Plan Test Results									
Delie Liller Teek		Conditions		Sample Size/Fail					
Reliability Test		Conditions		L	ot#1	Lot#2	Lot#3		
**High Temp. Storage Bake		170C (420 hrs)			77/0	77/0	77/0		
**Biased HAST		130C/85%RH (96 Hrs)			77/0	77/0	77/0		
**Autoclave		121C, 2 atm (96 Hrs)			77/0	77/0	77/0		
**T/C -65C/150C		-65C/+150C (500 Cyc)			77/0	77/0	77/0		
Ball Bond Shear		76 balls, 3 units min			Pass	Pass	Pass		
Bond Pad Cratering Check					Pass	Pass	Pass		
Bond Pull		76 Wire, 3 units min			Pass	Pass	Pass		
Notes **- Preconditioning sequence: Level 3-260C.									

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com